Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
10/025,851	BANG, JEONG IL	
Examiner	Art Unit	
Gabriel L. Chu	2114	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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Text Search	6/3	$\pi$
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IEEE, ACM	5(31	2